

IN THE CLAIMS:

The following is a complete listing of claims in this application.

7. (currently amended) In a BAYER circuit including a preliminary agglomeration phase, a crystal growth phase and a classification phase, a process for controlling precipitation of alumina hydrate from a slurry resulting from introduction of recycled alumina trihydrate seed into an aluminate liquor, in which particle size quality of alumina hydrate produced in the circuit and circulating in feed tanks is monitored, comprising the steps of:

a) a calibration step including:

al) measuring, versus time, of:

~~cumulative percentage percent~~ of alumina hydrate particles circulating in the feed tanks in the circuit that are finer than $X2 \mu\text{m}$, ~~defined as CPFT $X2$~~ ; and

~~cumulative percentage percent~~ of alumina hydrate particles circulating in the feed tanks in the circuit that are finer than $X1 \mu\text{m}$, ~~defined as CPFT $X1$~~ ;

where $X1$ and $X2$ are predetermined particle sizes and $X1$ is smaller than $X2$; and

a2) determining a relationship R between ~~CPFT~~ percent finer than $X1$ and later changes in ~~CPFT~~ percent finer than $X2$, and defining upper and lower trigger thresholds of ~~CPFT~~ percent finer than $X1$ which correspond to maximum permissible variations in ~~CPFT~~ percent finer than $X2$; and

b) controlling the circuit, comprising measuring ~~CPFT~~ percent finer than $X2$ and ~~updating~~ forming a correlation between ~~CPFT~~ percent finer than $X2$ and the particle size of hydrate produced by the circuit, ~~regularly~~ measuring ~~CPFT~~ percent finer than $X1$ and ~~a regularly~~ updating of the relationship R , and causing corrective action to the slurry at

the beginning of precipitation when the measured value of ~~CPFT~~ percent finer than X1 reaches an updated trigger threshold, to bring the percent finer than X2 within the maximum permissible variation.

8. (previously presented) Process according to claim 7, wherein said corrective action includes modifying amount of solid in the slurry at the beginning of the precipitation.

9. (currently amended) Process according to claim 8, wherein the modifying comprises varying amounts of ~~aliquots of~~ pregnant aluminate liquor ~~feeding~~ fed to a first agglomeration tank and a first feed tank, ~~respectively.~~

10. (previously presented) Process according to claim 7, wherein X2 is greater than 40 μm and X1 is less than 20 μm .

11. (currently amended) Process according to claim 7, wherein the measurements of ~~CPFT~~ percent finer than X1 μm and ~~CPFT~~ percent finer than X2 μm are made on a slurry at the end of crystal growth phase.

12. (previously presented) Process according to claim 7, wherein pregnant aluminate liquor feeding a first agglomeration tank in the circuit has a caustic content less than or equal to 160 g of Na_2O /liter.

13. (currently amended) Process according to claim 7, wherein said calibration step comprises:

1) daily measuring ~~CPFT~~ percent finer than X1 in the slurry at ~~any a predetermined point of the feed tank series in the circuit,~~ which is used to produce a first particle size vs. time diagram represented by a curve $Y = \%X1(t)$;

2) daily measuring ~~CPFT~~ percent finer than X2 in the slurry at ~~any a predetermined point of the feed tank series in the circuit,~~ which is used to produce a second particle size vs. time diagram represented by a curve $Y = \%X2(t)$ and in which $X2 > X1$ is a value already known ~~for its good correlation~~

to be well correlated with the particle size of the hydrate produced;

3) creating of an empirical relation between the particle size vs. time diagrams, which characterizes the relation R as:

$$R(\%<X2(t), \%<X1(t-\tau)) = 0$$

where t is the time at which CPFT percent finer than X2 is measured and τ is a characteristic time interval estimated by observing an occurrence of a same accidental phenomenon on each curve $\%<X2(t)$ and $\%<X1(t-\tau)$; and

4) defining a maximum threshold and minimum threshold of CPFT percent finer than X1 obtained from the relation R and a maximum interval of the permissible variation of values of CPFT percent finer than X2.

14. (currently amended) Process according to claim 13, wherein said controlling comprises:

1) daily measuring CPFT percent finer than X1 in the slurry at ~~any~~ a predetermined point in the ~~feed tank series circuit~~, in order to complete the first particle size time diagram represented by the curve $Y = \%<X1(t)$;

2) daily measuring CPFT percent finer than X2 in the slurry at ~~any~~ a predetermined point in the ~~feed tank series circuit~~, in order to complete the first particle size time diagram represented by the curve $Y = \%<X2(t)$;

3) updating ~~of R~~ a relationship between curve $Y = \%<X1(t)$ and curve $Y = \%<X2(t)$ and the definition of trigger thresholds of CPFT percent finer than X1; and

4) triggering of a corrective action to modify amount of solid in the slurry at the beginning of the precipitation when the measured value of CPFT percent finer than X1 reaches one of the thresholds defined in 3).